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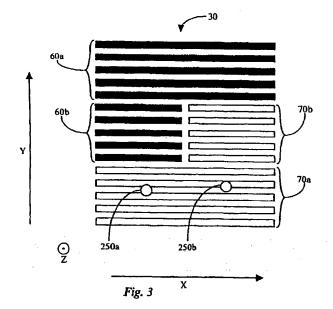
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(54) Overlay alignment measurement of semiconductor wafers

(57) The present invention is a new target, and associated apparatus and methods, for determining offset between adjacent layers of a semiconductor device. The target disclosed here includes a first periodic structure to be placed on a first layer of the device and a second periodic structure, that complements the first periodic structure, placed on a second layer of the

device at a location that is adjacent the first periodic structure when the second layer is placed on the first layer. Any offset that may occur is detected by the present invention either optically, micro-mechanically or with electron beams using any of various methods and system embodiments.





EUROPEAN SEARCH REPORT

Application Number EP 97 30 5036

1		ERED TO BE RELEVANT			
Category	Citation of document with it of relevant pass	ndication, where appropriate, ages	Relevant to claim	CLASSIFICATION OF THE APPLICATION (Int.CI.6)	
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A	Trigures 3,4 T		9,16-19, 23, 25-27, 29,44,45		
X	* page 3. line 3 - * page 4. line 10 - figures 1-7 * * page 11. line 55	ON KK) 2 October 1991 line 8 * page 7, line 24; - page 13, line 42;	1,2		
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ANNEX TO THE EUROPEAN SEARCH REPORT ON EUROPEAN PATENT APPLICATION NO.

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